Scientific Research Journal of Electromagnetic **Analysis and Applications** ISSN: 1942-0749

Special Issue on

Electromagnetic Measurement and Testing Technology

Call for Papers

Electromagnetic measurements are measurements of ambient (surrounding) electromagnetic fields that are performed using particular sensors or probes, such as EMF meters. Electromagnetic measurements are nowadays becoming important and widespread in different sectors to assess environmental and human exposure to non-ionizing radiation in many contexts. On the other hand, Electromagnetic Testing (ET) is a form of nondestructive testing (NDT) for pipelines that use the process of inducing electric currents / magnetic fields either inside or on the surface of a pipeline to measure an electromagnetic response. By creating these fields, defects inside the wall of the pipeline can be measured by analyzing specific electromagnetic signatures produced. The term "Electromagnetic Testing" is often intended to mean simply Eddy-Current Testing (ECT). However with an expanding number of electromagnetic and magnetic test methods, "Electromagnetic Testing" is more often used to mean the whole class of electromagnetic test methods, of which Eddy-Current Testing is just one.

In this special issue, we invite front-line researchers and authors to submit original research and review articles that explore Electromagnetic Measurement and Testing Technology.

Authors should read over the journal's Authors' Guidelines carefully before submission. Prospective authors should submit an electronic copy of their complete manuscript through the journal's Paper Submission System.

Please kindly notice that the "Special Issue" under your manuscript title is supposed to be specified and the research field "Special Issue - Electromagnetic Measurement and Testing Technology" should be chosen during your submission.

According to the following timetable:

Submission Deadline	November 30th, 2013
Publication Date	January 2014

Guest Editor:

For further questions or inquiries Please contact Editorial Assistant at jemaa@scirp.org